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L Number	Hits	Search Text	DB	Time stamp
1	7523	(714/25,30,43,44,724,728,733-735,738,739,742).ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/22 16:41
2	5	((714/25,30,43,44,724,728,733-735,738,739,742).ccls.) and ((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device)))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not ((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device)))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/22 16:48
-	370	interface and (Britt Harris Dooley).XA.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 15:18
-	44538	714/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 15:18
-	70	(interface and (Britt Harris Dooley).XA.) and 714/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 15:18
-	94	(interface near4 (circuit device)) and (Britt Harris Dooley).XA.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 15:19
-	32	((interface near4 (circuit device)) and (Britt Harris Dooley).XA.) and 714/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 15:58
-	435	(((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 16:24
-	1	((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device)))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) and (\$6random near6 generat\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 16:06
-	42	(((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device)))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 16:25
-	626	(((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device)))) same (self-test "self test" self\$1test)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 16:24
-	51	(((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device)))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 16:30

-	0	((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not (((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 16:30
-	0	((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not (((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 16:30
-	9	((((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal))) not (((((bidirectional\$2 bi-directional\$2) near4 (buffer device circuit)) or (interface near4 (circuit device))) same (self-test "self test" self\$1test)) and (compar\$3 near4 (prescribed expect\$2) near4 (signature data signal)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/22 16:47
-	84	(((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) same (interface near4 (circuit device)) same (self-test "self test" self\$1test))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 13:46
-	1		USPAT; US-PGPUB	2004/07/21 10:08
-	1		USPAT; US-PGPUB	2004/07/21 10:08
-	1		USPAT; US-PGPUB	2004/07/21 10:09
-	1		USPAT; US-PGPUB	2004/07/21 10:10
-	1		USPAT; US-PGPUB	2004/07/21 10:12
-	1		USPAT; US-PGPUB	2004/07/21 10:12
-	1		USPAT; US-PGPUB	2004/07/21 10:12
-	1		USPAT; US-PGPUB	2004/07/21 10:12
-	1		USPAT; US-PGPUB	2004/07/21 10:13
-	1		USPAT; US-PGPUB	2004/07/21 10:13
-	1		USPAT; US-PGPUB	2004/07/21 10:14
-	1		USPAT; US-PGPUB	2004/07/21 10:14
-	1		USPAT; US-PGPUB	2004/07/21 10:15
-	1		USPAT; US-PGPUB	2004/07/21 10:15
-	1		USPAT; US-PGPUB	2004/07/21 10:15
-	1		USPAT; US-PGPUB	2004/07/21 10:15
-	1		USPAT; US-PGPUB	2004/07/21 10:25
-	1		USPAT; US-PGPUB	2004/07/21 10:26

-	1		USPAT; US-PGPUB	2004/07/21 10:26
-	1		USPAT; US-PGPUB	2004/07/21 10:27
-	1		USPAT; US-PGPUB	2004/07/21 10:27
-	1		USPAT; US-PGPUB	2004/07/21 10:28
-	1		USPAT; US-PGPUB	2004/07/21 10:28
-	1		USPAT; US-PGPUB	2004/07/21 10:28
-	1		USPAT; US-PGPUB	2004/07/21 10:28
-	1		USPAT; US-PGPUB	2004/07/21 10:39
-	1		USPAT; US-PGPUB	2004/07/21 10:39
-	1		USPAT; US-PGPUB	2004/07/21 10:39
-	1		USPAT; US-PGPUB	2004/07/21 10:40
-	12	((US-6704897-\$ or US-6587976-\$ or US-6560734-\$ or US-6421801-\$ or US-5621739-\$ or US-5167020-\$ or US-5717701-\$ or US-6477674-\$).did. or (US-20020112206-\$ or US-20030080769-\$ or US-20030120989-\$ or US-20030101376-\$).did.	USPAT; US-PGPUB	2004/07/21 13:44
-	1	((US-6704897-\$ or US-6587976-\$ or US-6560734-\$ or US-6421801-\$ or US-5621739-\$ or US-5167020-\$ or US-5717701-\$ or US-6477674-\$).did. or (US-20020112206-\$ or US-20030080769-\$ or US-20030120989-\$ or US-20030101376-\$).did.) and MISR	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 13:45
-	1	((US-6704897-\$ or US-6587976-\$ or US-6560734-\$ or US-6421801-\$ or US-5621739-\$ or US-5167020-\$ or US-5717701-\$ or US-6477674-\$).did. or (US-20020112206-\$ or US-20030080769-\$ or US-20030120989-\$ or US-20030101376-\$).did.) and ("multiple input shift register" MISR)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 13:47
-	1	((bidirectional\$2 bi-directional\$2 I/O) near4 (buffer device circuit)) same (interface near4 (circuit device)) same (self-test "self test" self\$1test)) and ("multiple input shift register" MISR)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 16:05
-	3	((US-6704897-\$ or US-6587976-\$ or US-6560734-\$ or US-6421801-\$ or US-5621739-\$ or US-5167020-\$ or US-5717701-\$ or US-6477674-\$).did. or (US-20020112206-\$ or US-20030080769-\$ or US-20030120989-\$ or US-20030101376-\$).did.) and ("multiple input shift register" MISR signature)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 13:55
-	4	((US-6704897-\$ or US-6587976-\$ or US-6560734-\$ or US-6421801-\$ or US-5621739-\$ or US-5167020-\$ or US-5717701-\$ or US-6477674-\$).did. or (US-20020112206-\$ or US-20030080769-\$ or US-20030120989-\$ or US-20030101376-\$).did.) and ("multiple input shift register" MISR signature compact\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 13:56
-	1	(bidirectional\$2 bi-directional\$2) same (interface near4 (circuit device)) same (self-test "self test" self\$1test) and (LFSR)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 14:09
-	13	(interface near4 (circuit device)) same (self-test "self test" self\$1test) and (LFSR)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 14:11

-	31	(interface near4 (circuit device)) same (self-test "self test" self\$1test) and ("linear feedback shift register" LFSR)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 14:11
-	26	(interface near4 (circuit device)) same (self-test "self test" self\$1test) and ("linear feedback shift register" LFSR) and ("multiple input shift register" MISR signature)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 14:25
-	596	("low voltage differential signals" LVDS "double data rate" DDR) near4 interface	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/22 13:48
-	3	((("low voltage differential signals" LVDS "double data rate" DDR) near4 interface) and (self-test "self test" self\$1test) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)) and ("multiple input shift register" MISR signature)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 14:28
-	13	((("low voltage differential signals" LVDS "double data rate" DDR) near4 interface) and (self-test "self test" self\$1test) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)"pseudo random generator"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 14:28
-	3	((("low voltage differential signals" LVDS "double data rate" DDR) near4 interface) and (self-test "self test" self\$1test) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)"pseudo random generator") and ("multiple input shift register" MISR signature)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 16:08
-	2	(DE-19832307\$ DE-19901460\$).did.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 14:59
-	62	(I/O near4 interface) same self-test\$7	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 16:06
-	0	((I/O near4 interface) same self-test\$7) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)"pseudo random generator") and ("multiple input shift register" MISR signature)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 16:08
-	11	((I/O near4 interface) same self-test\$7) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)"pseudo random generator")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 16:11
-	51	((I/O near4 interface) same self-test\$7) not (((I/O near4 interface) same self-test\$7) and ("linear feedback shift register" LFSR (pattern near2 generat\$4)"pseudo random generator"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/21 16:11
-	5	("low voltage differential signals" LVDS "double data rate" DDR) near4 self-test\$7 and (volt\$3 power)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/22 10:47
-	2221	(separate independent isolated) near4 ((supply near4 voltage) or ((power voltage) near4 supply)) same (buffer I/O interface VDD\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/22 13:03

-	1	((separate independent isolated) near4 ((supply near4 voltage) or ((power voltage) near4 supply)) same (buffer I/O interface VDD\$4)) and ("low voltage differential signals" LVDS "double data rate" DDR) same self-test\$7	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/22 10:48
-	50	((separate independent isolated) near4 ((supply near4 voltage) or ((power voltage) near4 supply)) same (buffer I/O interface VDD\$4)) and self-test\$7	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/22 10:49
-	1167	((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/22 14:07
-	3	((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4)) and DUT near4 board	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/22 13:16
-	1		USPAT; US-PGPUB	2004/07/22 13:14
-	1		USPAT; US-PGPUB	2004/07/22 13:14
-	1		USPAT; US-PGPUB	2004/07/22 13:14
-	5	((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4)) and ((DUT load) near4 board)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/22 13:23
-	90	((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4)) and test\$3 near4 (IC "integrated circuit" semiconductor)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/22 13:59
-	106	("low voltage differential signals" LVDS) same PLL	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/22 13:49
-	2	("low voltage differential signals" LVDS) same PLL) and LFSR	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/22 13:49
-	133	((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4)) and interference	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/22 13:59
-	44	((separate independent isolated) near4 ((power voltage) near4 supply)) same (buffer I/O VDD\$4)) and interference same supply	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/22 14:07
-	147	((power voltage) near4 supply) same ((buffer I/O VDD\$4) near4 ring)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/22 16:40
-	1		USPAT; US-PGPUB	2004/07/22 15:01
-	1		USPAT; US-PGPUB	2004/07/22 15:02
-	1		USPAT; US-PGPUB	2004/07/22 15:02

-	1		USPAT; US-PGPUB	2004/07/22 15:03
-	1		USPAT; US-PGPUB	2004/07/22 15:03
-	1		USPAT; US-PGPUB	2004/07/22 15:03
-	1		USPAT; US-PGPUB	2004/07/22 15:03